6/A
J. Douglas
3/29/01

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants:	Blaine R. Spady, Robert Buchanan, and Richard A. Yarussi		
Assignee:	Nanometrics Incorporated		
Title:	System Using A Polar Coordinate Stage And Continuous Image Rotation To Compensate For Stage Rotation		
Serial No.:	09/113,484	Filing Date:	July 10, 1998
Examiner:	R. Lee	Group Art Unit:	2613
Docket No.:	M-5955 US		

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MAR 20 2001
PATENT & TRADEMARK OFFICE

San Jose, California
March 19, 2001

BOX No Fee
COMMISSIONER FOR PATENTS
Washington, D. C. 20231

RESPONSE TO OFFICE ACTION

Dear Sir:

This is a response to the December 19, 2000 Office Action, which has a statutorily shortened period for response that ends March 19, 2001.

IN THE SPECIFICATION

Please replace the paragraph starting on page 1, line 23 with the following replacement paragraph.

A1

The space required to accommodate the range of motion of an X,Y stage has a width that is equal to or greater than the width of the sample plus the travel distance in the X direction and a length that is equal to or greater than the length of the sample plus the travel distance in the Y direction. Fig. 1 illustrates a system 100 that uses an X,Y stage to position a circular sample 110. System 100 includes an imaging and/or measurement system (not shown) that can be, for example, a video camera, a microscope, an interferometer, a reflectometer, an ellipsometer, an FTIR spectrometer, or any type of spectrophotometer. Such systems typically have a field of view 130 that is much smaller than sample 110. To view the left edge of sample 110, the X,Y stage moves sample 110 to a position 112 where the left

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